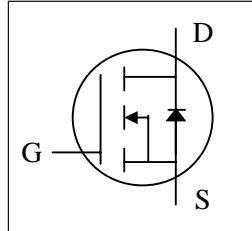
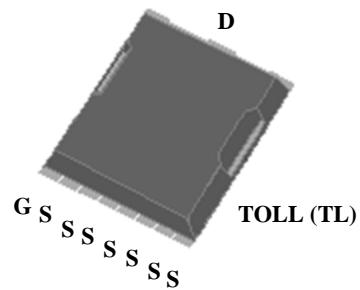


- ▼ 100% R_g & UIS Test
- ▼ Simple Drive Requirement
- ▼ Ultra Low On-resistance
- ▼ RoHS Compliant & Halogen-Free



BV_{DSS}	100V
$R_{DS(ON)}$	2mΩ



Description

XP10NB2R0 series are innovated design and silicon process technology to achieve the lowest possible on-resistance and fast switching performance. It provides the designer with an extreme efficient device for use in a wide range of power applications.

The TOLL package is a perfect solution for high power density and high power efficiency application.

Absolute Maximum Ratings@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	100	V
V_{GS}	Gate-Source Voltage	+20	V
$I_D @ T_C = 25^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}$	247	A
$I_D @ T_C = 100^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}$	175	A
I_{DM}	Pulsed Drain Current ¹	1000	A
$P_D @ T_C = 25^\circ\text{C}$	Total Power Dissipation	250	W
$P_D @ T_A = 25^\circ\text{C}$	Total Power Dissipation ³	3.75	W
E_{AS}	Single Pulse Avalanche Energy ⁵	500	mJ
T_{STG}	Storage Temperature Range	-55 to 175	°C
T_J	Operating Junction Temperature Range	-55 to 175	°C

Thermal Data

Symbol	Parameter	Value	Units
R_{thj-c}	Maximum Thermal Resistance, Junction-case	0.6	°C/W
R_{thj-a}	Maximum Thermal Resistance, Junction-ambient (PCB mount) ³	40	°C/W

Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_D=250\mu\text{A}$	100	-	-	V
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=10\text{V}$, $I_D=100\text{A}$	-	-	2	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_D=250\mu\text{A}$	2	-	4	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=5\text{V}$, $I_D=100\text{A}$	-	210	-	S
I_{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}=80\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	25	uA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}=\pm 20\text{V}$, $V_{\text{DS}}=0\text{V}$	-	-	± 0.1	uA
Q_g	Total Gate Charge ⁴	$I_D=100\text{A}$	-	136	217.6	nC
Q_{gs}	Gate-Source Charge ⁴	$V_{\text{DS}}=50\text{V}$	-	36	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge ⁴	$V_{\text{GS}}=10\text{V}$	-	42	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time ⁴	$V_{\text{DS}}=50\text{V}$	-	28	-	ns
t_r	Rise Time ⁴	$I_D=100\text{A}$	-	115	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time ⁴	$R_G=6\Omega$	-	91	-	ns
t_f	Fall Time ⁴	$V_{\text{GS}}=10\text{V}$	-	218	-	ns
C_{iss}	Input Capacitance ⁴	$V_{\text{GS}}=0\text{V}$	-	7600	12160	pF
C_{oss}	Output Capacitance ⁴	$V_{\text{DS}}=80\text{V}$	-	1085	-	pF
C_{rss}	Reverse Transfer Capacitance ⁴	f=1.0MHz	-	30	-	pF
R_g	Gate Resistance	f=1.0MHz	-	0.6	1.2	Ω

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$I_S=100\text{A}$, $V_{\text{GS}}=0\text{V}$	-	-	1.3	V
t_{rr}	Reverse Recovery Time ⁴	$I_S=100\text{A}$, $V_{\text{GS}}=0\text{V}$	-	118	-	ns
Q_{rr}	Reverse Recovery Charge ⁴	dl/dt=100A/ μs	-	225	-	nC

Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Surface mounted on 1 in² copper pad of FR4 board
- 4.Guaranteed by design.
- 5.Starting $T_j=25^\circ\text{C}$, $V_{\text{DD}}=50\text{V}$, $L=0.1\text{mH}$, $R_G=25\Omega$, $V_{\text{GS}}=10\text{V}$
- 6.These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{j(\text{MAX})}=175^\circ\text{C}$.

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT, AUTOMOTIVE OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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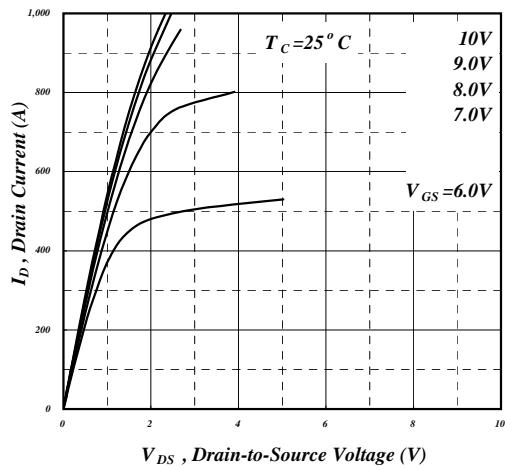


Fig 1. Typical Output Characteristics

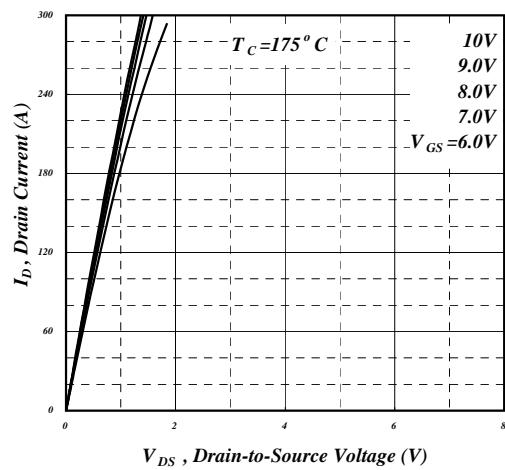


Fig 2. Typical Output Characteristics

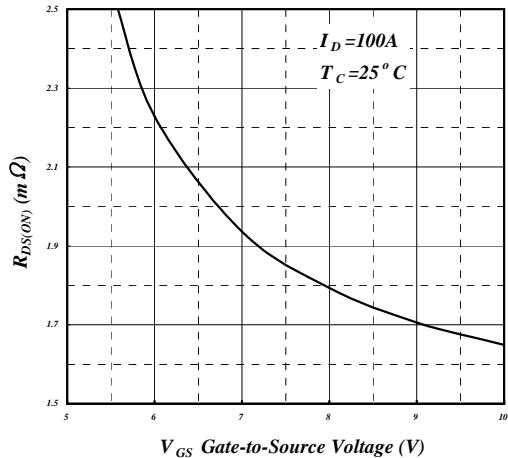


Fig 3. On-Resistance v.s. Gate Voltage

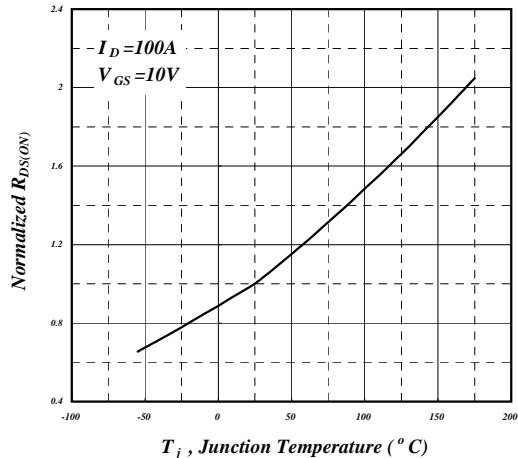


Fig 4. Normalized On-Resistance v.s. Junction Temperature

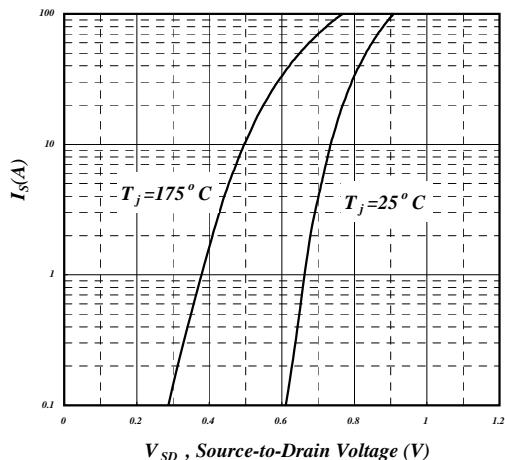


Fig 5. Forward Characteristic of Reverse Diode

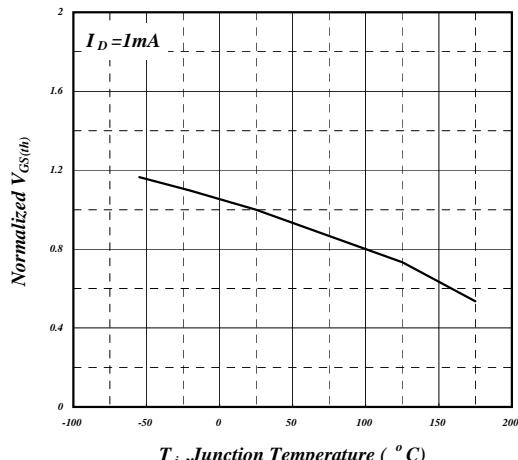


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

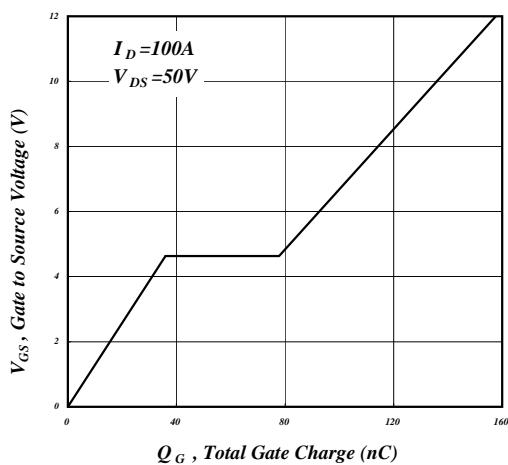


Fig 7. Gate Charge Characteristics

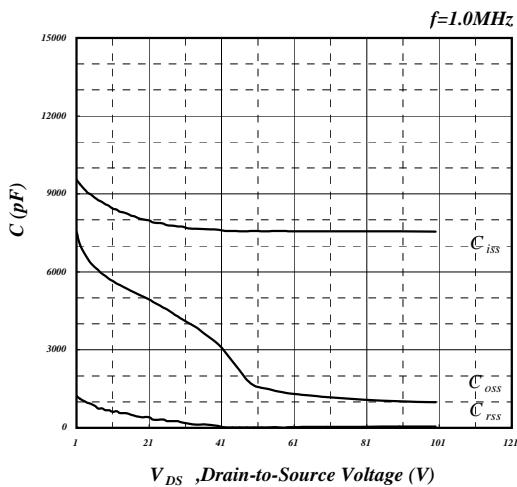


Fig 8. Typical Capacitance Characteristics

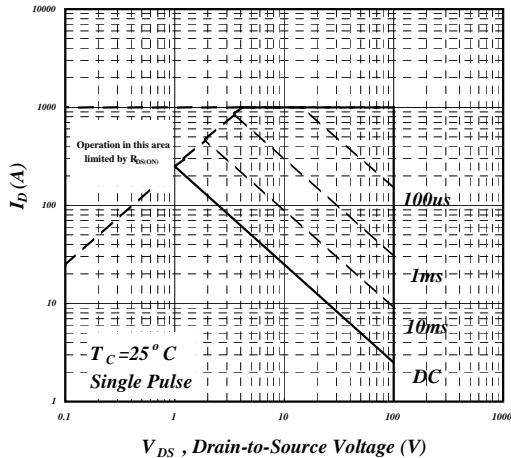


Fig 9. Maximum Safe Operating Area⁶

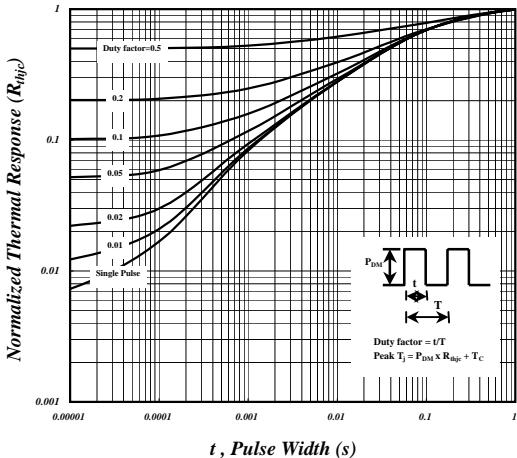


Fig 10. Effective Transient Thermal Impedance

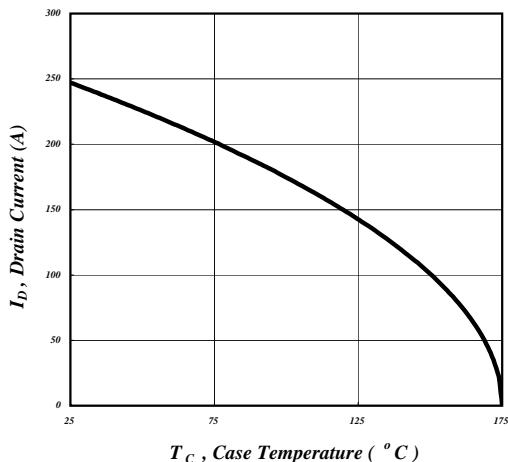


Fig 11. Drain Current v.s. Case Temperature

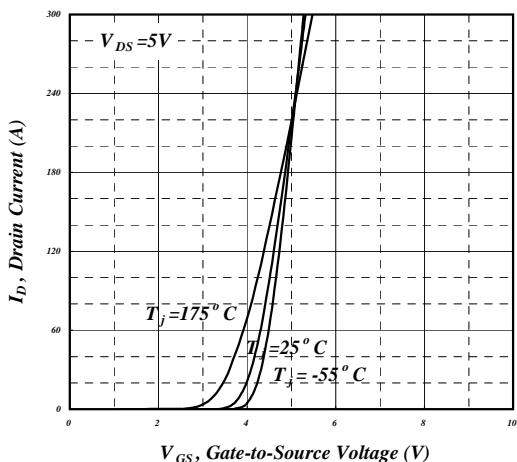


Fig 12. Transfer Characteristics

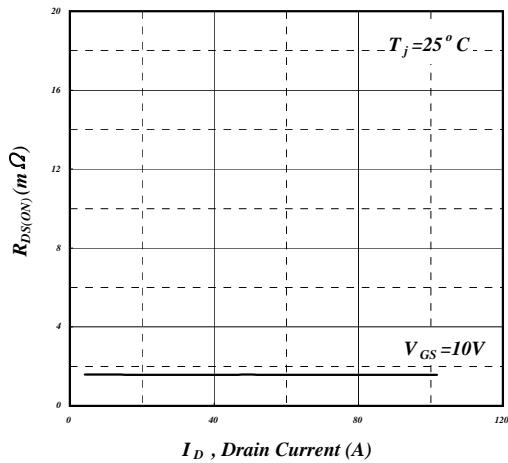


Fig 13. Typ. Drain-Source on State Resistance

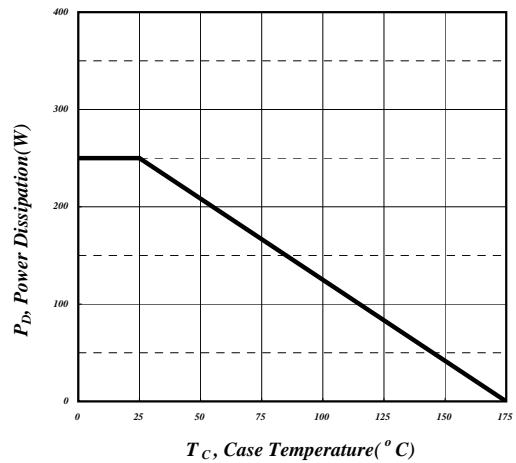
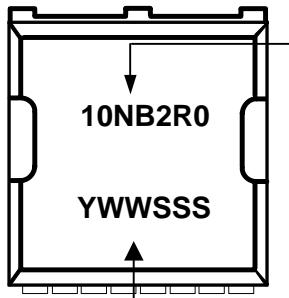


Fig 14. Total Power Dissipation

MARKING INFORMATION

Part Number

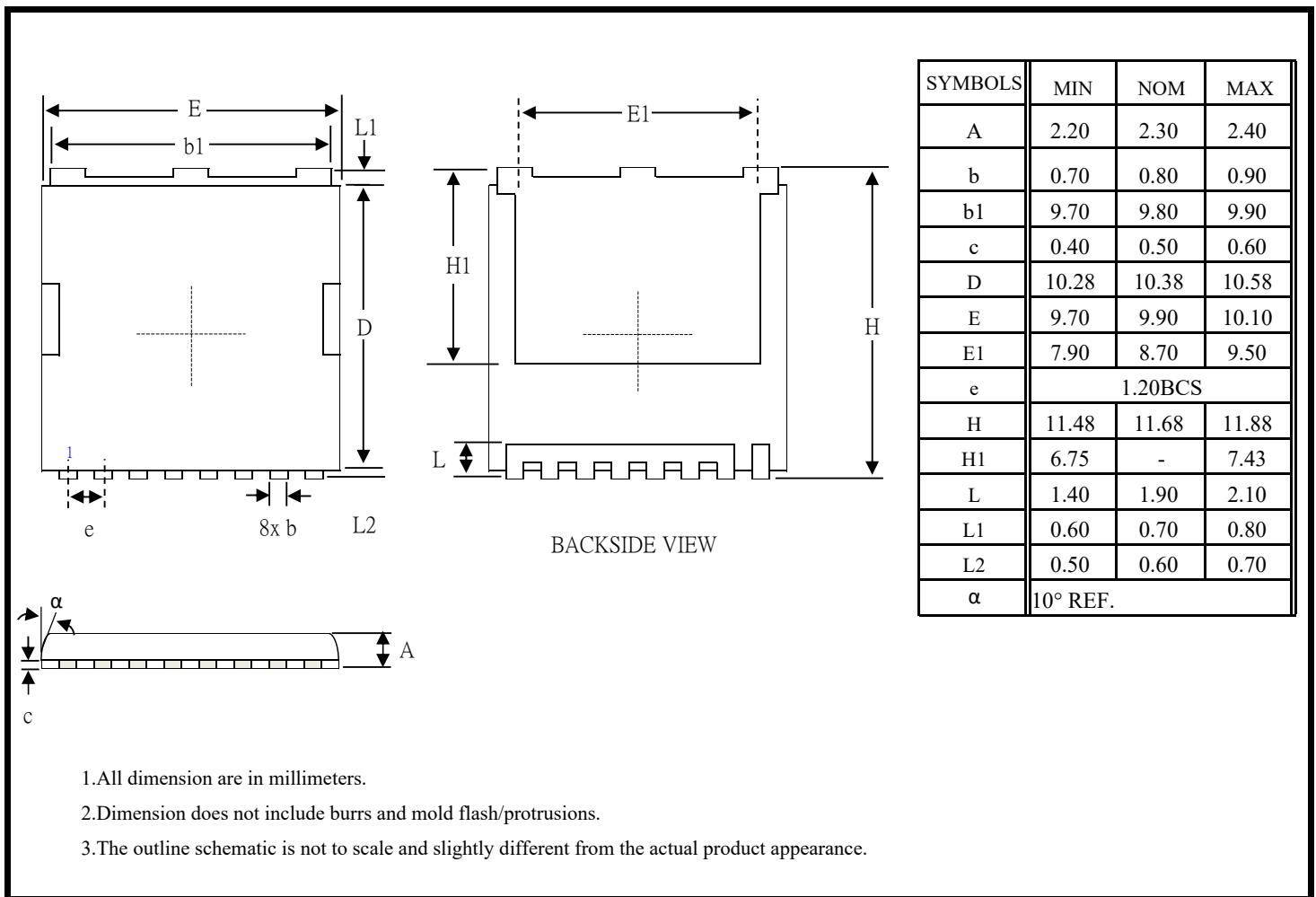
Date Code (YWWSSS)

Y : Last Digit Of The Year

WW : Week

SSS : Sequence

Package Outline : TOLL



Draw No. M1-TL-8-EFIM-G-V04

TOLL FOOTPRINT :

